

# P09 LTE B13\_QPSK10M\_Right Cheek\_Ch23230\_1RB\_OS24

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 13	LTE-FDD, -	782.000, 23230	9.13	0.925	41.9

## Hardware Setup

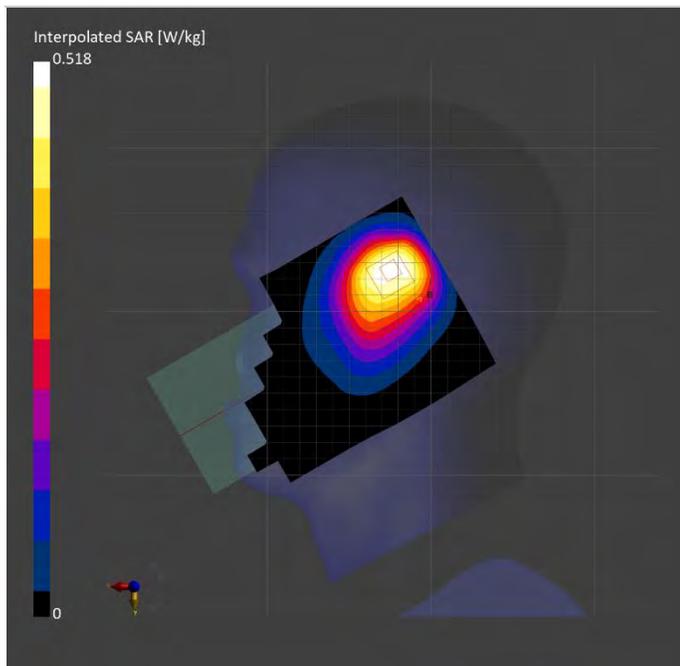
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-08-25	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-25	2025-08-25
psSAR1g [W/kg]	0.445	0.411
psSAR10g [W/kg]	0.304	0.246
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.6
Dist 3dB Peak [mm]		10.8



# P10 LTE B26\_QPSK15M\_Right Cheek\_Ch26765\_1RB\_OS0

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 26	LTE-FDD, -	821.500, 26765	8.95	0.930	42.6

## Hardware Setup

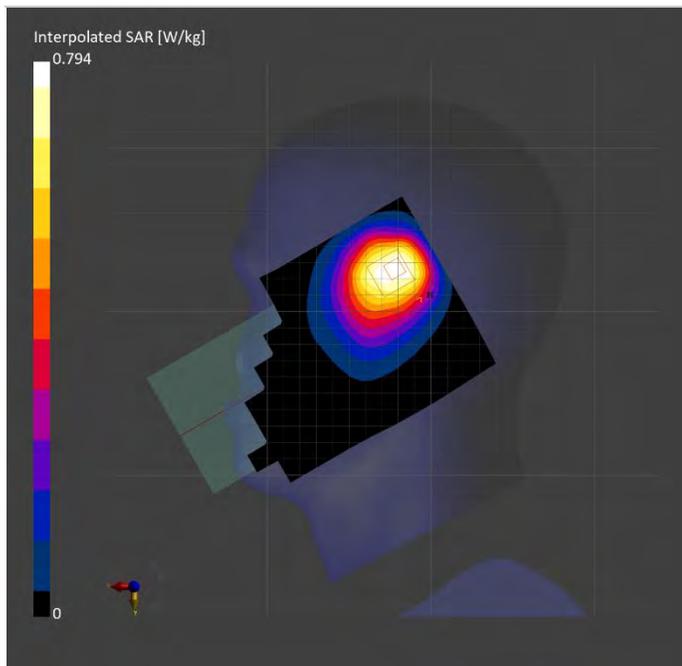
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.683	0.715
psSAR10g [W/kg]	0.465	0.424
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.9
Dist 3dB Peak [mm]		8.5



# P11 LTE B41\_QPSK20M\_Right Cheek\_Ch40620\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	CHEEK, 0.00	Band 41	LTE-TDD, -	2593.000, 40620	6.55	2.00	38.2

## Hardware Setup

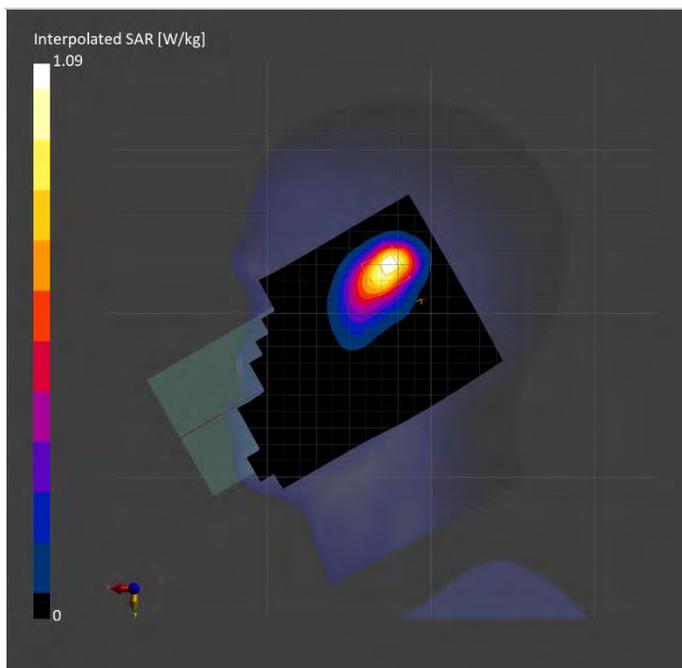
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-08-28	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-28	2025-08-28
psSAR1g [W/kg]	0.812	0.844
psSAR10g [W/kg]	0.403	0.407
Power Drift [dB]	0.03	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		10.8



# P12 LTE B66\_QPSK20M\_Right Tilted\_Ch132572\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead, -	TILT, 0.00	Band 66	LTE-FDD, -	1770.000, 132572	7.45	1.39	40.2

## Hardware Setup

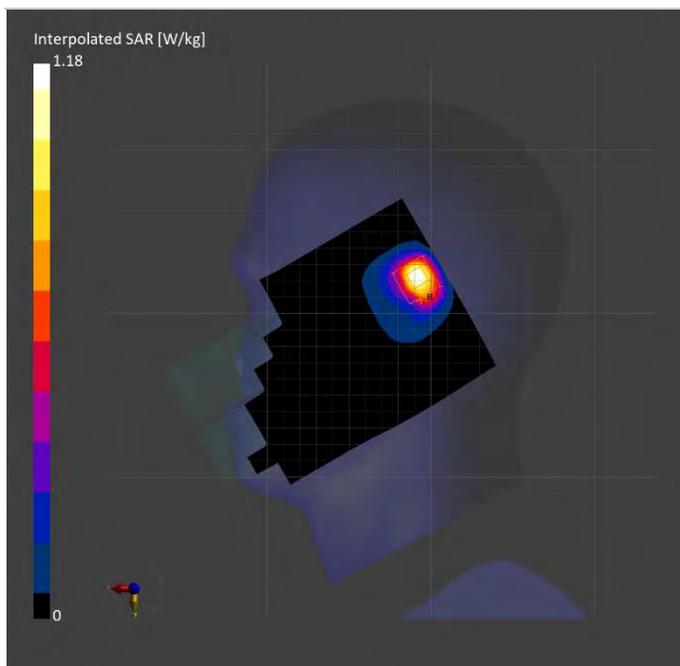
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-08-27	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-27	2025-08-27
psSAR1g [W/kg]	0.882	0.871
psSAR10g [W/kg]	0.431	0.408
Power Drift [dB]	-0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.6
Dist 3dB Peak [mm]		8.5



# P13 WLAN2.4G\_802.11b\_Left Cheek\_Ch1

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	6.69	1.80	38.4

## Hardware Setup

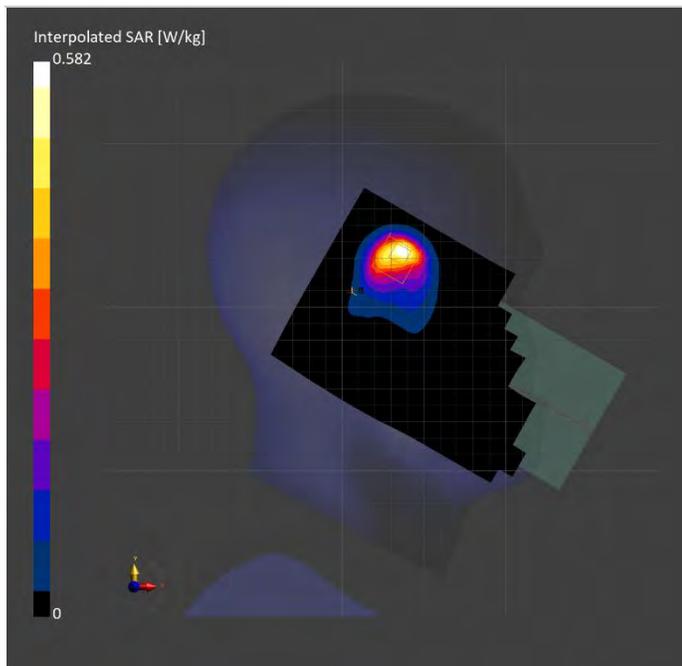
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.415	0.442
psSAR10g [W/kg]	0.200	0.194
Power Drift [dB]	-0.05	0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.4
Dist 3dB Peak [mm]		7.2



# P14 WLAN5G\_802.11a\_Left Cheek\_Ch60

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5300.000, 60	5.14	4.70	35.0

## Hardware Setup

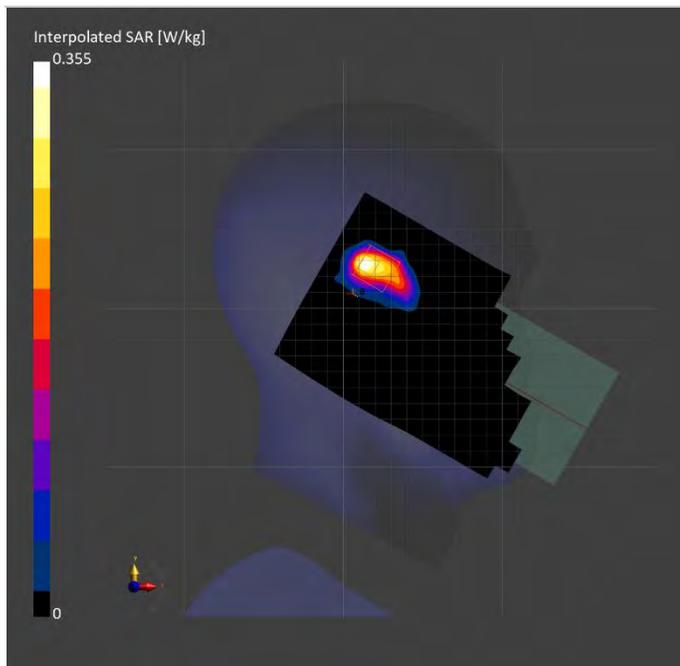
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-08-31	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-31	2025-08-31
psSAR1g [W/kg]	0.235	0.257
psSAR10g [W/kg]	0.085	0.080
Power Drift [dB]	0.16	0.13
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.1
Dist 3dB Peak [mm]		6.7



# P15 WLAN5G\_802.11a\_Left Cheek\_Ch132

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5660.000, 132	4.75	5.13	34.4

## Hardware Setup

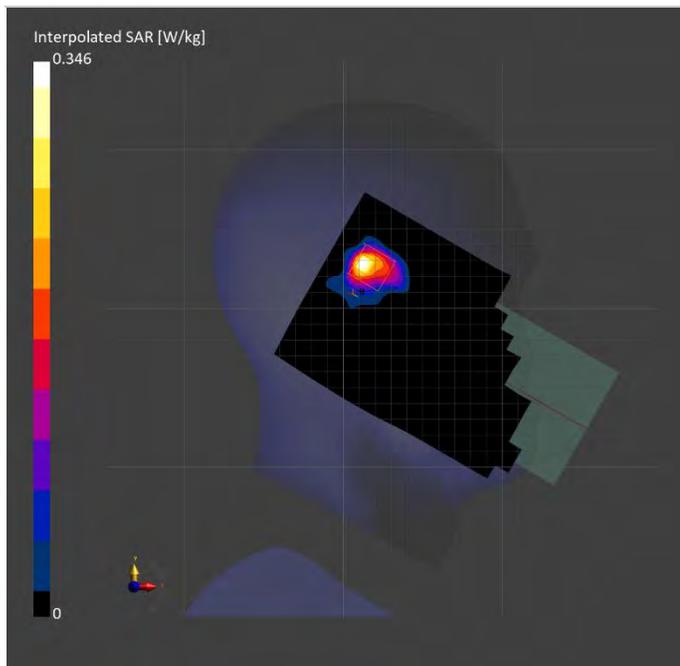
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-09-01	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-01	2025-09-01
psSAR1g [W/kg]	0.224	0.278
psSAR10g [W/kg]	0.076	0.074
Power Drift [dB]	0.18	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		54.3
Dist 3dB Peak [mm]		6.1



# P16 WLAN5G\_802.11a\_Left Cheek\_Ch165

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	WLAN 5GHz	WLAN, -	5825.000, 165	4.83	5.20	34.3

## Hardware Setup

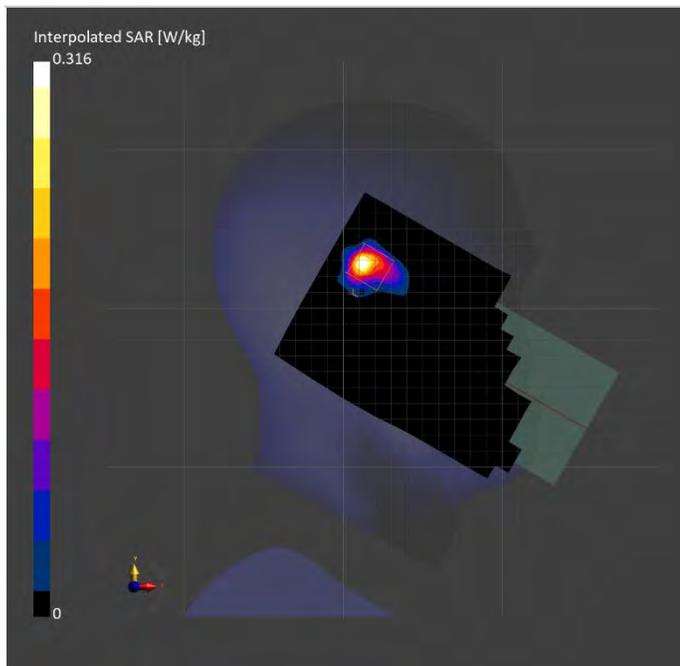
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-09-01	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-01	2025-09-01
psSAR1g [W/kg]	0.204	0.230
psSAR10g [W/kg]	0.064	0.060
Power Drift [dB]	0.08	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		49.3
Dist 3dB Peak [mm]		6.2



# P17 BT\_GFSK\_Left Cheek\_Ch39

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead, -	CHEEK, 0.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	6.69	1.82	38.4

## Hardware Setup

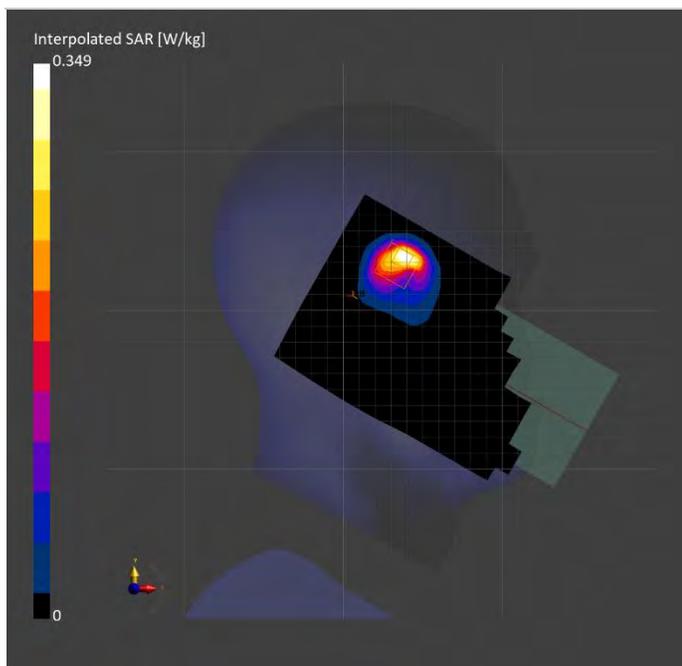
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.246	0.269
psSAR10g [W/kg]	0.113	0.113
Power Drift [dB]	0.11	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.8
Dist 3dB Peak [mm]		6.4



# P18 GSM850\_GPRS 4Tx Slot\_Rear Face\_1.5cm\_Ch128

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	GSM 850	GSM, -	824.200, 128	8.95	0.931	42.6

## Hardware Setup

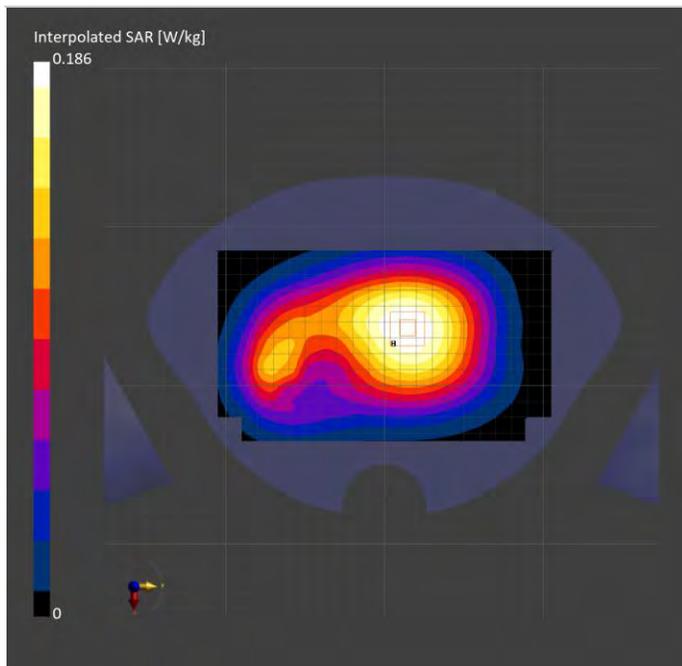
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.164	0.176
psSAR10g [W/kg]	0.116	0.134
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		91.1
Dist 3dB Peak [mm]		> 15.0



# P19 GSM1900\_GPRS 4Tx Slot\_Rear Face\_1.5cm\_Ch810

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	PCS 1900	GSM, -	1909.800, 810	7.22	1.47	40.3

## Hardware Setup

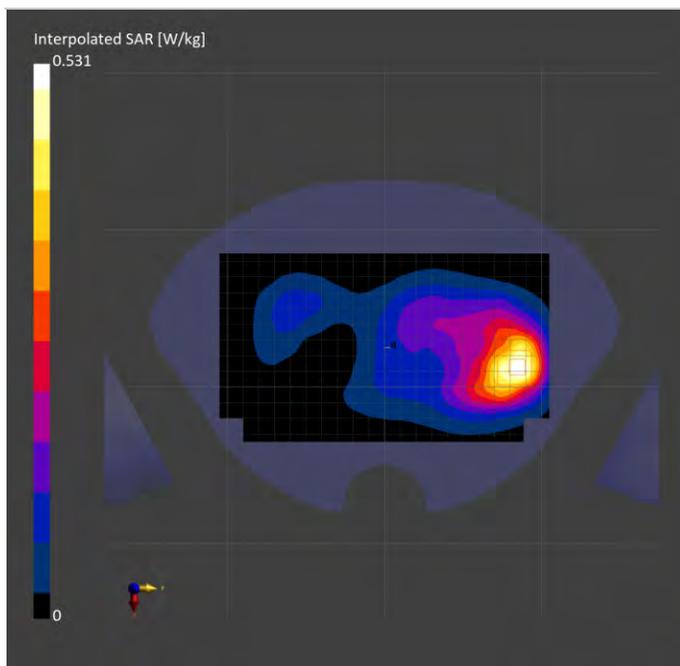
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-08-29	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-29	2025-08-29
psSAR1g [W/kg]	0.434	0.472
psSAR10g [W/kg]	0.250	0.265
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.3
Dist 3dB Peak [mm]		13.0



# P20 WCDMA II\_RMC12.2K\_Rear Face\_1.5cm\_Ch9400

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	WCDMA, -	1880.000, 9400	7.22	1.47	40.3

## Hardware Setup

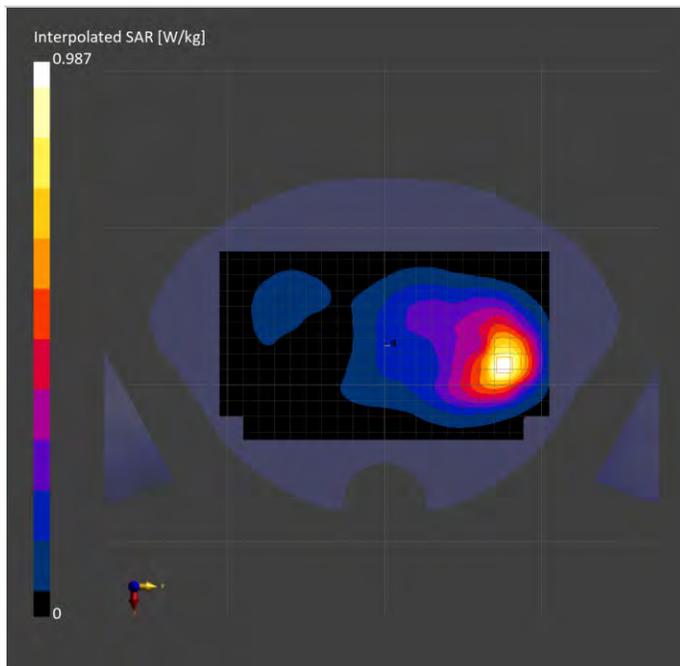
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-08-29	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-29	2025-08-29
psSAR1g [W/kg]	0.795	0.841
psSAR10g [W/kg]	0.449	0.473
Power Drift [dB]	-0.04	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.4
Dist 3dB Peak [mm]		11.9



# P21 WCDMA IV\_RMC12.2K\_Rear Face\_1.5cm\_Ch1413

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 4	WCDMA, -	1732.600, 1413	7.45	1.37	40.2

## Hardware Setup

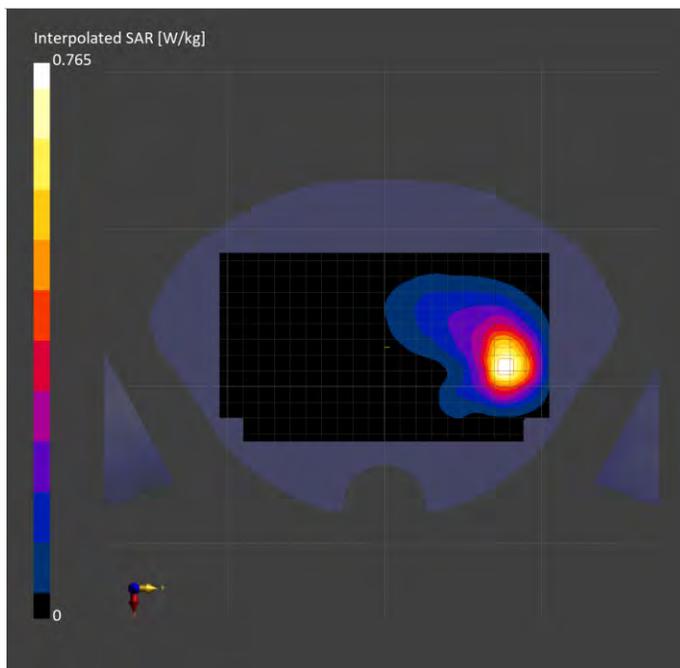
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-08-27	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-27	2025-08-27
psSAR1g [W/kg]	0.623	0.672
psSAR10g [W/kg]	0.353	0.380
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		86.3
Dist 3dB Peak [mm]		13.2



# P22 WCDMA V\_RMC12.2K\_Rear Face\_1.5cm\_Ch4233

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 5	WCDMA, -	846.600, 4233	8.95	0.940	42.5

## Hardware Setup

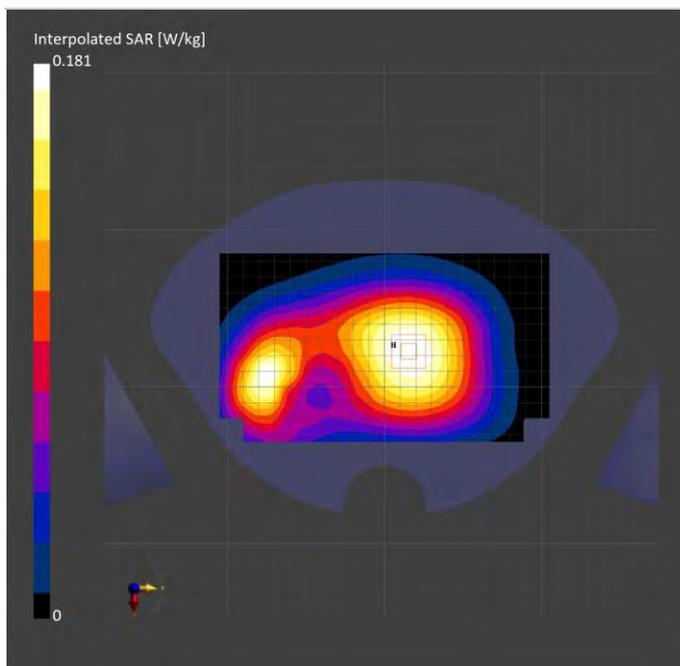
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.160	0.170
psSAR10g [W/kg]	0.113	0.131
Power Drift [dB]	-0.01	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		91.8
Dist 3dB Peak [mm]		> 15.0



# P23 LTE B2\_QPSK20M\_Rear Face\_1.5cm\_Ch18900\_1RB\_OS50

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 2	LTE-FDD, -	1880.000, 18900	7.22	1.47	40.3

## Hardware Setup

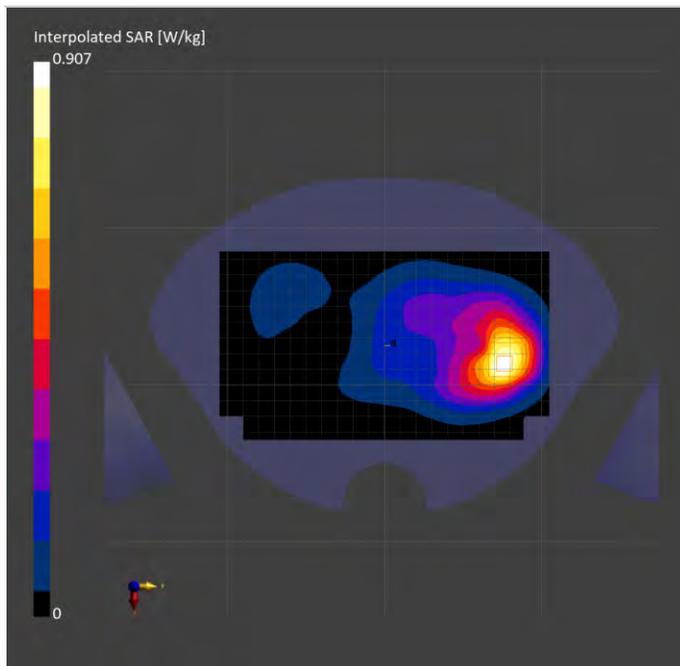
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-08-29	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-29	2025-08-29
psSAR1g [W/kg]	0.738	0.791
psSAR10g [W/kg]	0.422	0.448
Power Drift [dB]	-0.02	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		85.5
Dist 3dB Peak [mm]		12.4



# P24 LTE B7\_QPSK20M\_Rear Face\_1.5cm\_Ch20850\_1RB\_OS50

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 7	LTE-FDD, -	2510.000, 20850	6.55	1.93	38.4

## Hardware Setup

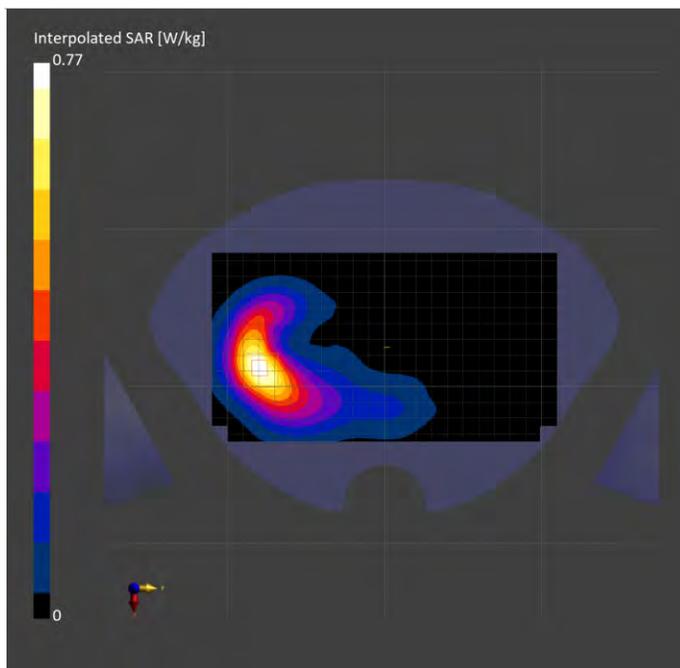
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-08-28	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-28	2025-08-28
psSAR1g [W/kg]	0.612	0.611
psSAR10g [W/kg]	0.323	0.326
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		83.2
Dist 3dB Peak [mm]		12.9



P25 LTE B12\_QPSK10M\_Rear Face\_1.5cm\_Ch23060\_1RB\_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK, 15.00	Band 12	LTE-FDD,	704.000, 23060	9.13	0.900	42.2

Hardware Setup

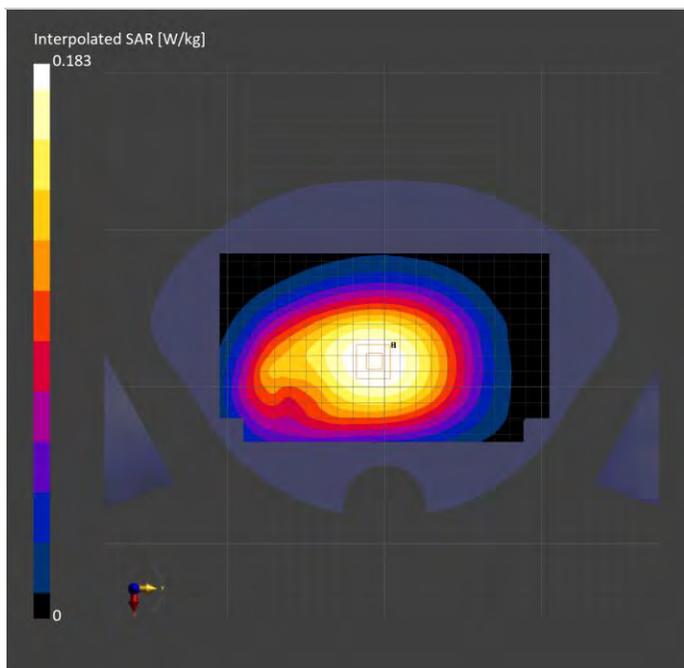
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-08-25	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-25	2025-08-25
psSAR1g [W/kg]	0.163	0.175
psSAR10g [W/kg]	0.117	0.137
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		92.4
Dist 3dB Peak [mm]		> 15.0



# P26 LTE B13\_QPSK10M\_Rear Face\_1.5cm\_Ch23230\_1RB\_OS24

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 13	LTE-FDD, -	782.000, 23230	9.13	0.925	41.9

## Hardware Setup

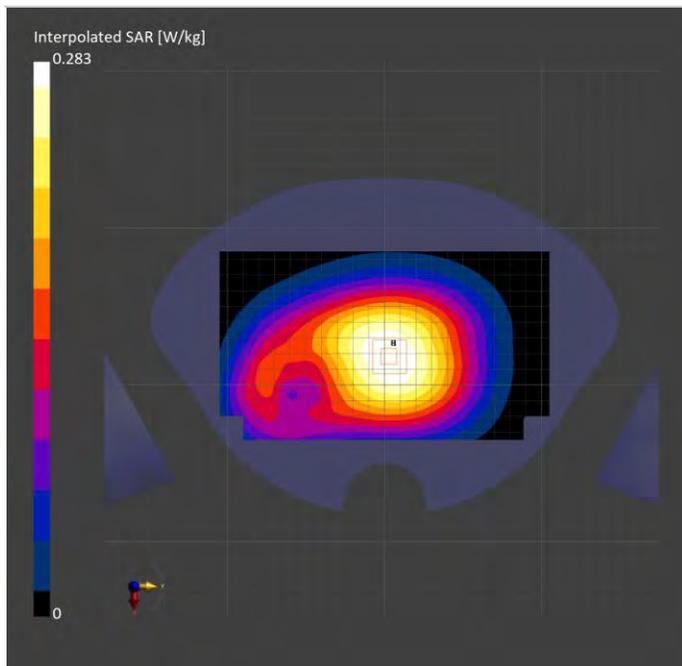
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-08-25	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-25	2025-08-25
psSAR1g [W/kg]	0.251	0.267
psSAR10g [W/kg]	0.178	0.208
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		90.3
Dist 3dB Peak [mm]		> 15.0



P27 LTE B26\_QPSK15M\_Rear Face\_1.5cm\_Ch26765\_1RB\_OS37

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 26	LTE-FDD, -	821.500, 26765	8.95	0.930	42.6

Hardware Setup

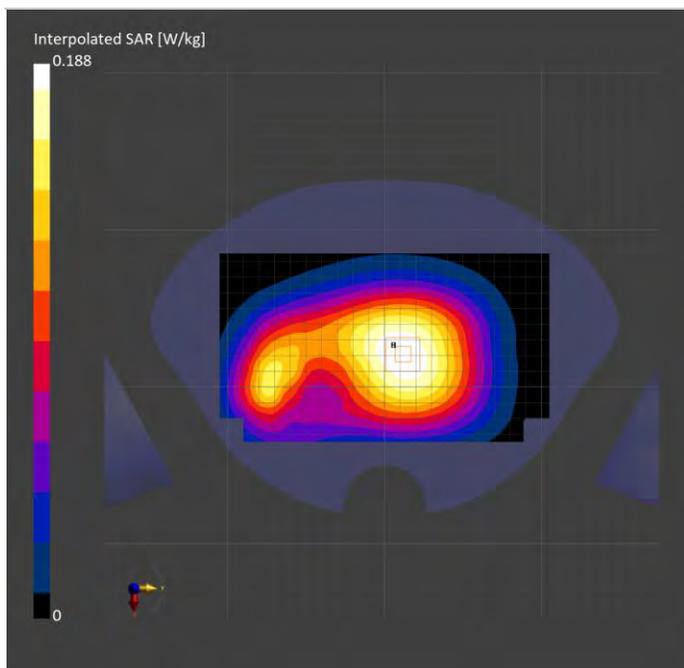
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.166	0.178
psSAR10g [W/kg]	0.117	0.137
Power Drift [dB]	0.03	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.1
Dist 3dB Peak [mm]		> 15.0



# P28 LTE B41\_QPSK20M\_Rear Face\_1.5cm\_Ch39750\_1RB\_OS50

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 41	LTE-TDD, -	2506.000, 39750	6.55	1.92	38.4

## Hardware Setup

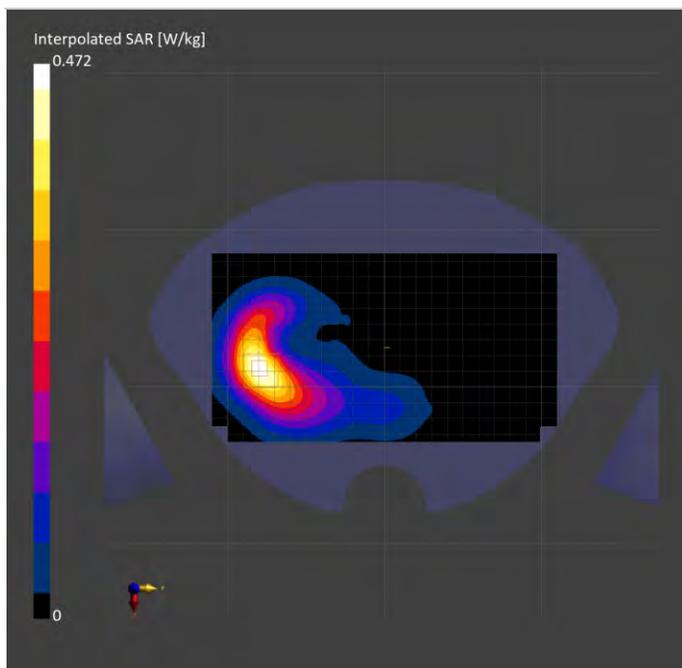
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-08-28	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-28	2025-08-28
psSAR1g [W/kg]	0.376	0.384
psSAR10g [W/kg]	0.199	0.204
Power Drift [dB]	0.08	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		12.8



# P29 LTE B66\_QPSK20M\_Rear Face\_1.5cm\_Ch132072\_1RB\_OS50

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	Band 66	LTE-FDD, -	1720.000, 132072	7.45	1.36	40.3

## Hardware Setup

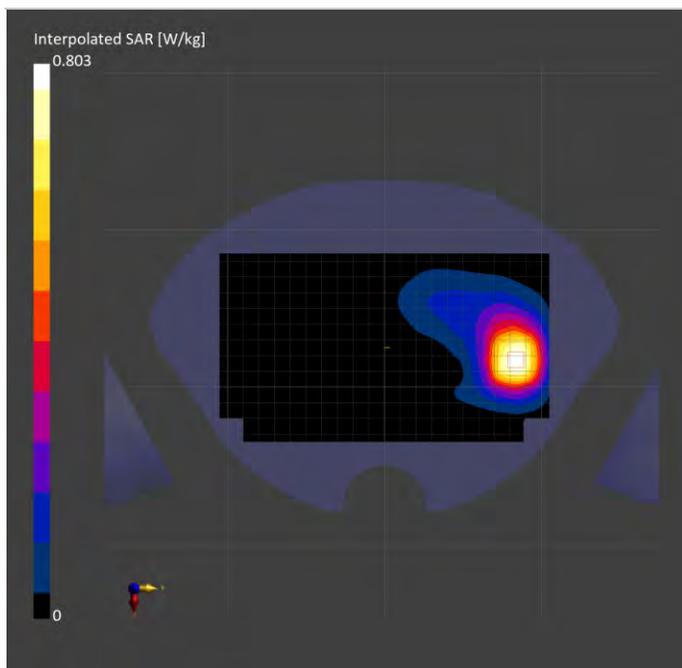
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-08-27	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-27	2025-08-27
psSAR1g [W/kg]	0.680	0.769
psSAR10g [W/kg]	0.399	0.433
Power Drift [dB]	-0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		86.5
Dist 3dB Peak [mm]		13.0



# P30 WLAN2.4G\_802.11b\_Rear Face\_1.5cm\_Ch1

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 2.4GHz	WLAN, -	2412.000, 1	6.69	1.80	38.4

## Hardware Setup

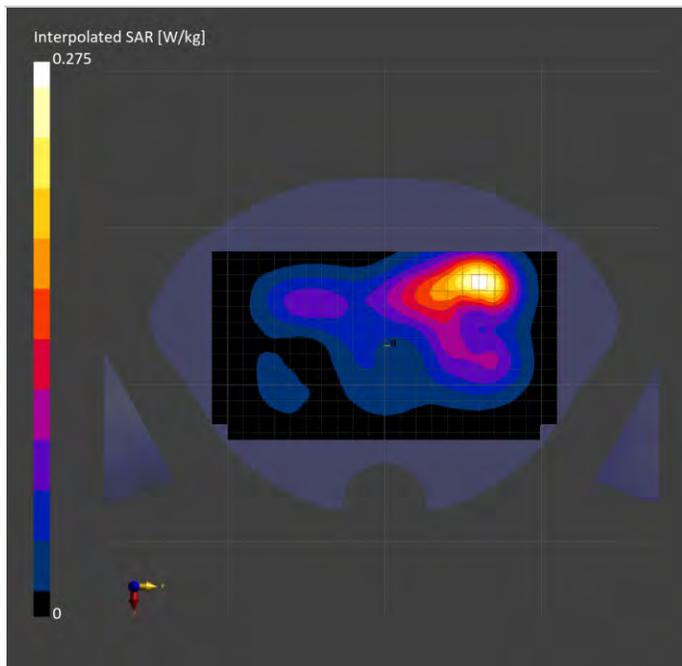
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.216	0.220
psSAR10g [W/kg]	0.112	0.115
Power Drift [dB]	0.05	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		12.4



# P31 WLAN5G\_802.11a\_Front Face\_1.5cm\_Ch60

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	FRONT, 15.00	WLAN 5GHz	WLAN, -	5300.000, 60	5.14	4.70	35.0

## Hardware Setup

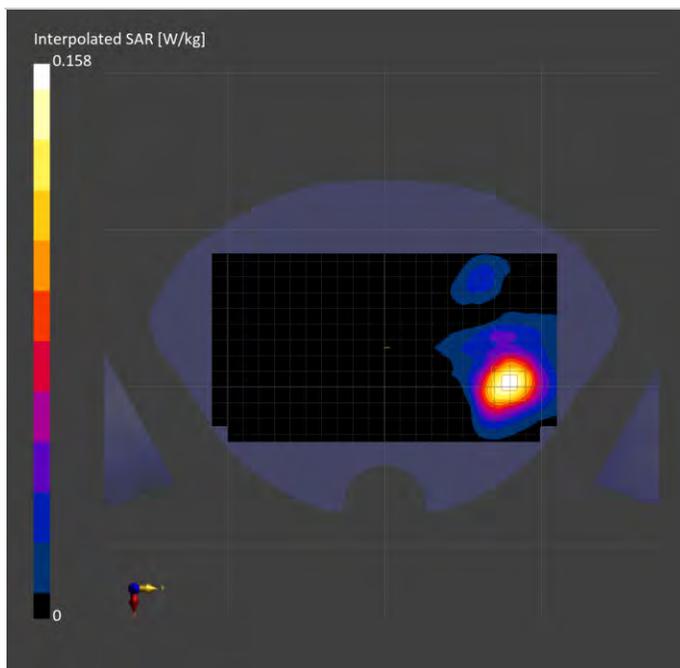
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-08-31	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-31	2025-08-31
psSAR1g [W/kg]	0.117	0.112
psSAR10g [W/kg]	0.048	0.042
Power Drift [dB]	-0.05	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		57.3
Dist 3dB Peak [mm]		12.0



# P32 WLAN5G\_802.11a\_Rear Face\_1.5cm\_Ch132

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5660.000, 132	4.75	5.13	34.4

## Hardware Setup

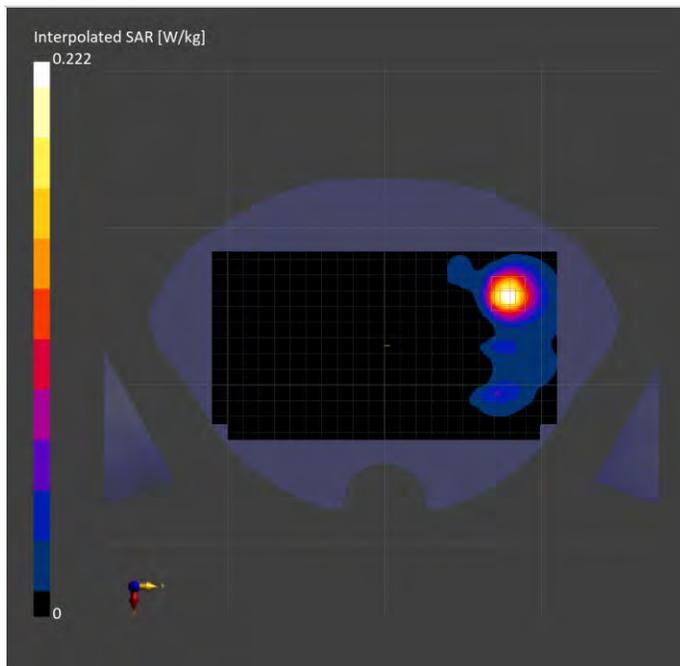
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-09-01	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-01	2025-09-01
psSAR1g [W/kg]	0.159	0.148
psSAR10g [W/kg]	0.058	0.051
Power Drift [dB]	-0.17	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		54.9
Dist 3dB Peak [mm]		9.2



# P33 WLAN5G\_802.11a\_Rear Face\_1.5cm\_Ch165

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	WLAN 5GHz	WLAN, -	5825.000, 165	4.83	5.20	34.3

## Hardware Setup

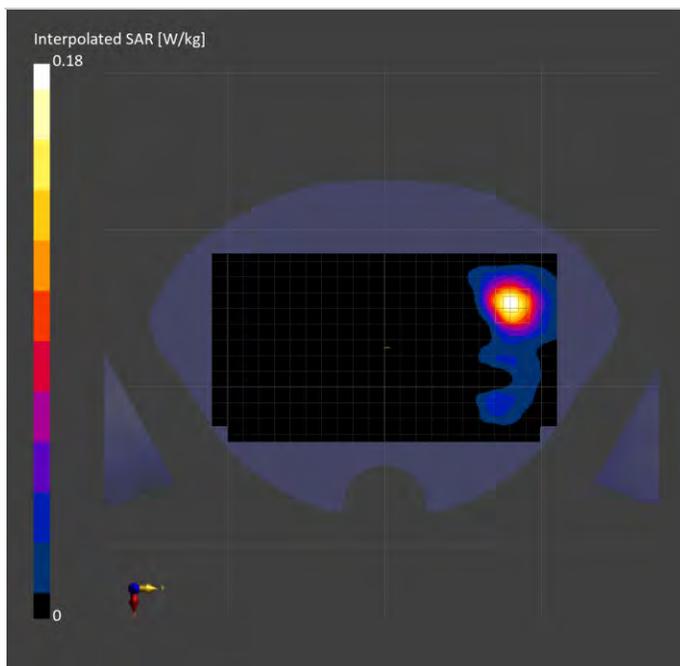
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-09-01	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-01	2025-09-01
psSAR1g [W/kg]	0.130	0.133
psSAR10g [W/kg]	0.048	0.045
Power Drift [dB]	-0.13	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		60.2
Dist 3dB Peak [mm]		10.5



## P34 BT\_GFSK\_Rear Face\_1.5cm\_Ch39

### Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

### Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 15.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	6.69	1.82	38.4

### Hardware Setup

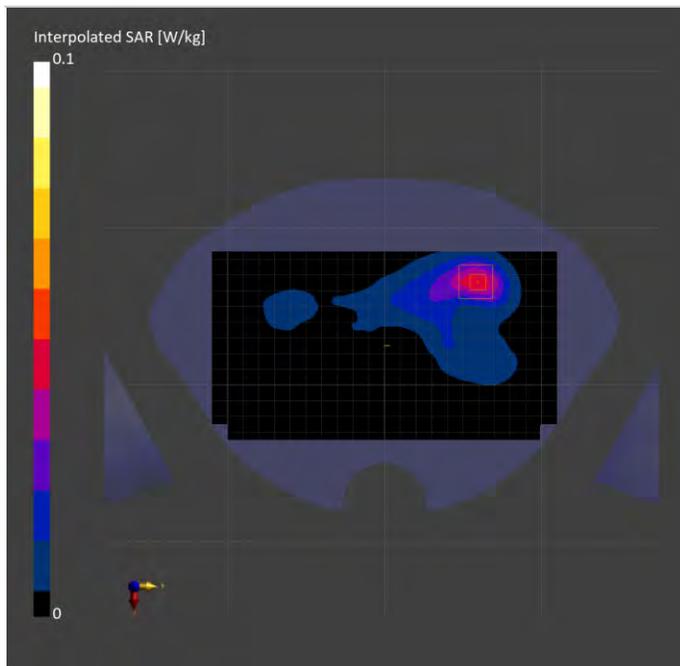
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

### Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

### Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.039	0.040
psSAR10g [W/kg]	0.019	0.020
Power Drift [dB]	-0.09	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.3
Dist 3dB Peak [mm]		11.2



# P35 GSM850\_GPRS 4Tx Slot\_Rear Face\_1cm\_Ch128

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	GSM 850	GSM, -	824.200, 128	8.95	0.931	42.6

## Hardware Setup

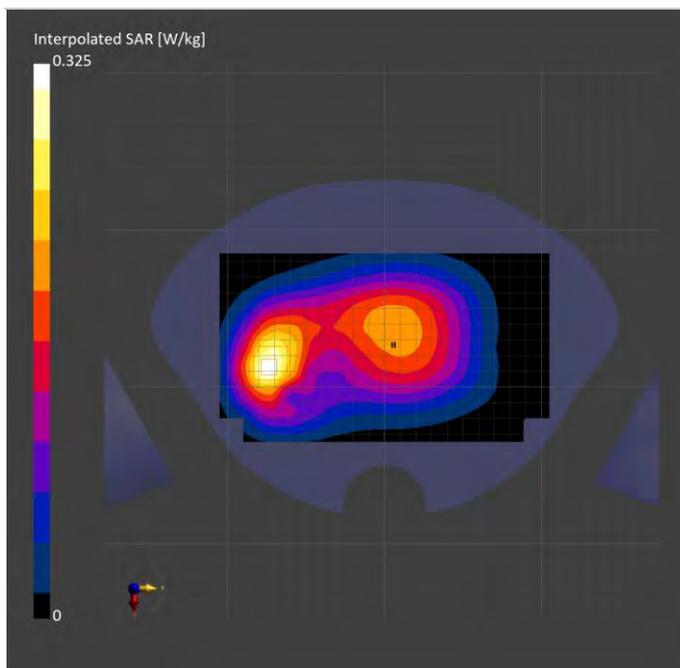
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.276	0.271
psSAR10g [W/kg]	0.177	0.166
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		14.0



# P36 GSM1900\_GPRS 4Tx Slot\_Bottom Side\_1cm\_Ch661

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	PCS 1900	GSM,	1880.000, 661	7.22	1.47	40.3

## Hardware Setup

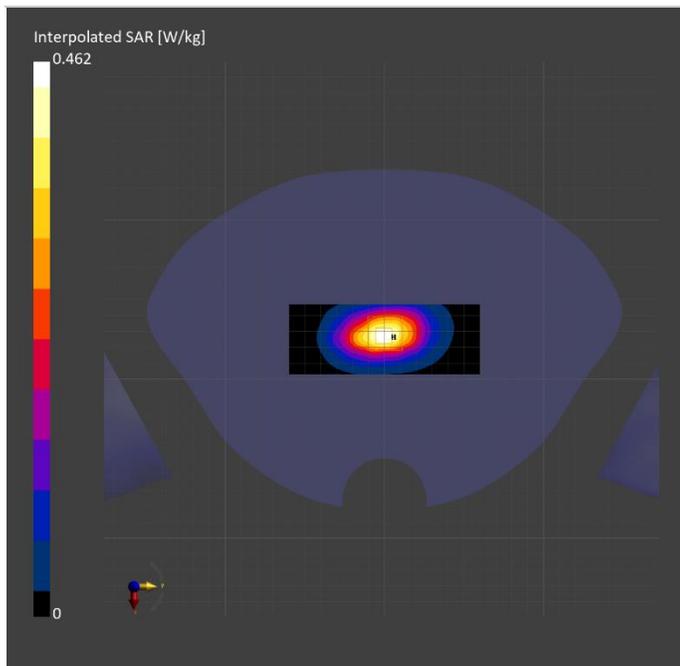
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-09-03	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-03	2025-09-03
psSAR1g [W/kg]	0.369	0.399
psSAR10g [W/kg]	0.197	0.212
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		84.2
Dist 3dB Peak [mm]		9.9



# P37 WCDMA II\_RMC12.2K\_Bottom Side\_1cm\_Ch9400

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE BOTTOM, 10.00	Band 2	WCDMA, -	1880.000, 9400	7.22	1.47	40.3

## Hardware Setup

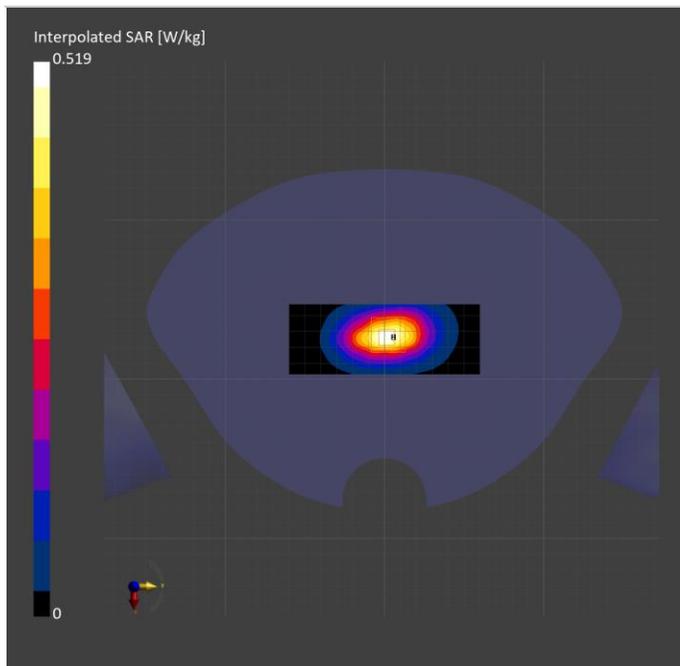
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-09-03	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-03	2025-09-03
psSAR1g [W/kg]	0.412	0.439
psSAR10g [W/kg]	0.219	0.236
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		85.1
Dist 3dB Peak [mm]		10.8



# P38 WCDMA IV\_RMC12.2K\_Bottom Side\_1cm\_Ch1413

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	Band 4	WCDMA,	1732.600, 1413	7.45	1.31	38.3

## Hardware Setup

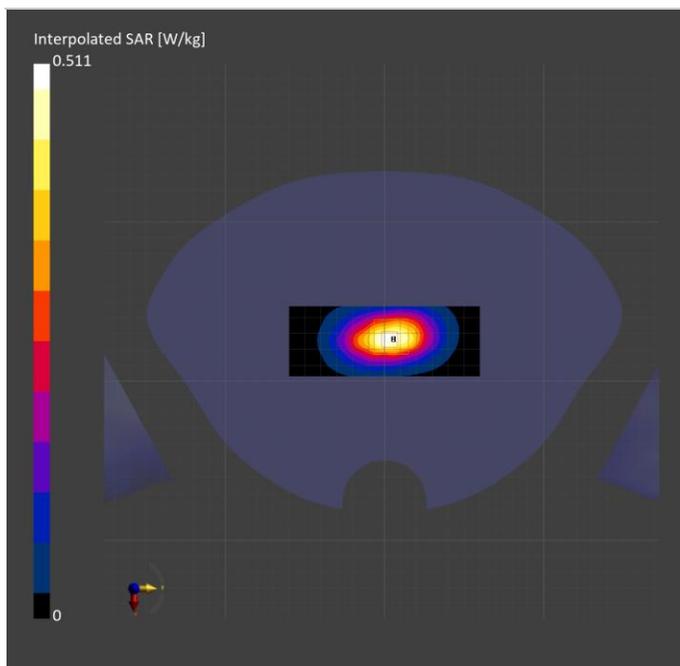
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-09-02	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-02	2025-09-02
psSAR1g [W/kg]	0.412	0.441
psSAR10g [W/kg]	0.224	0.242
Power Drift [dB]	-0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		85.7
Dist 3dB Peak [mm]		10.8



# P39 WCDMA V\_RMC12.2K\_Rear Face\_1cm\_Ch4233

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 5	WCDMA, -	846.600, 4233	8.95	0.940	42.5

## Hardware Setup

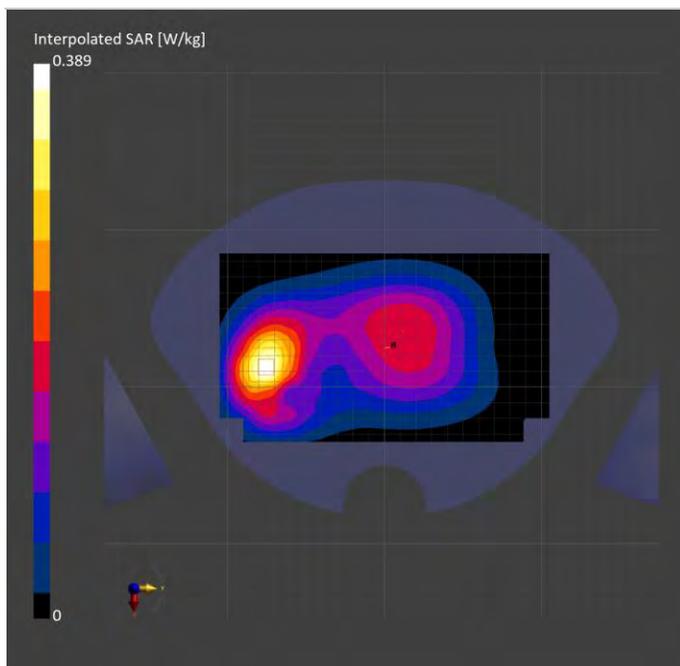
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.331	0.332
psSAR10g [W/kg]	0.210	0.203
Power Drift [dB]	-0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.2
Dist 3dB Peak [mm]		13.7



# P40 LTE B2\_QPSK20M\_Bottom Side\_1cm\_Ch18900\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	Band 2	LTE-FDD,	1880.000, 18900	7.22	1.47	40.3

## Hardware Setup

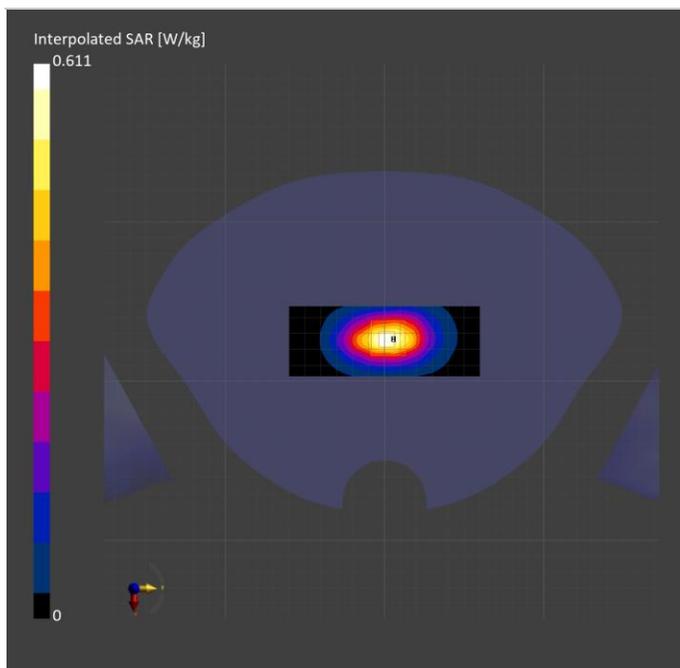
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1950-2025-09-03	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-03	2025-09-03
psSAR1g [W/kg]	0.484	0.513
psSAR10g [W/kg]	0.254	0.275
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.4
Dist 3dB Peak [mm]		10.8



# P41 LTE B7\_QPSK20M\_Bottom Side\_1cm\_Ch20850\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	Band 7	LTE-FDD,	2510.000, 20850	6.55	1.93	38.4

## Hardware Setup

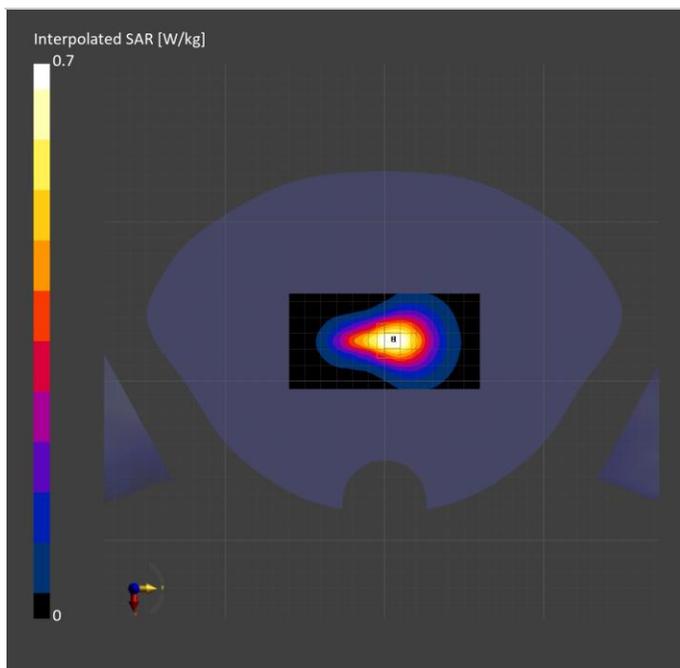
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-09-04	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-04	2025-09-04
psSAR1g [W/kg]	0.555	0.573
psSAR10g [W/kg]	0.276	0.289
Power Drift [dB]	-0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]	N/A	N/A
TSL Correction	No correction	No correction
M2/M1 [%]		80.2
Dist 3dB Peak [mm]		10.8



# P42 LTE B12\_QPSK10M\_Rear Face\_1cm\_Ch23060\_1RB\_OS24

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 12	LTE-FDD, -	704.000, 23060	9.13	0.900	42.2

## Hardware Setup

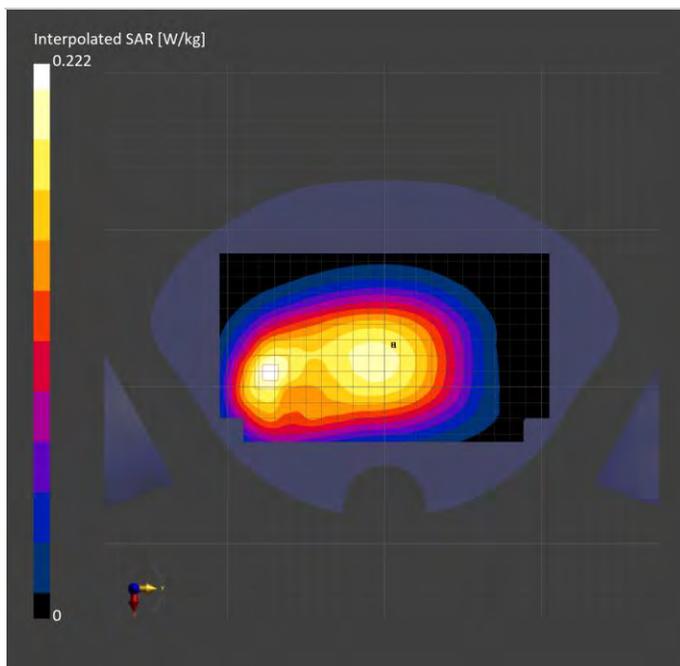
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-08-25	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-25	2025-08-25
psSAR1g [W/kg]	0.190	0.190
psSAR10g [W/kg]	0.126	0.119
Power Drift [dB]	-0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.8
Dist 3dB Peak [mm]		14.9



P43 LTE B13\_QPSK10M\_Rear Face\_1cm\_Ch23230\_1RB\_OS24

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 13	LTE-FDD, -	782.000, 23230	9.13	0.925	41.9

Hardware Setup

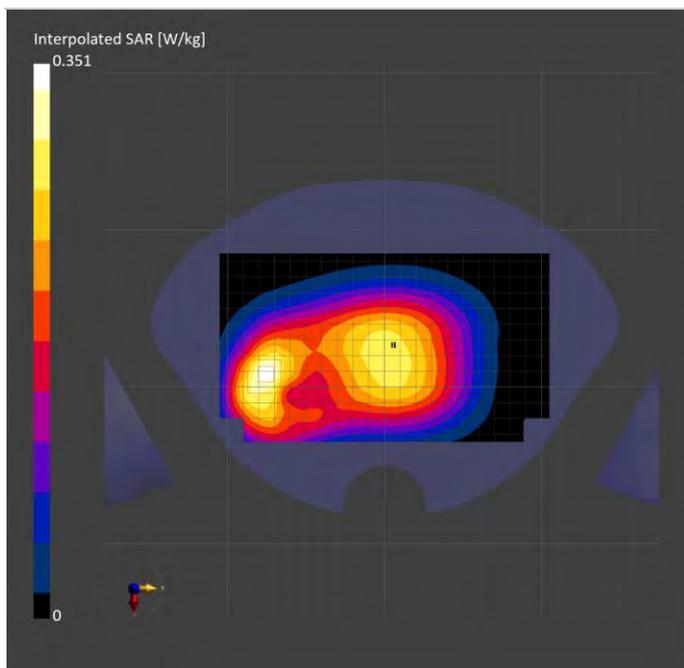
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL750-2025-08-25	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-25	2025-08-25
psSAR1g [W/kg]	0.298	0.308
psSAR10g [W/kg]	0.194	0.109
Power Drift [dB]	-0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.7
Dist 3dB Peak [mm]		14.5



# P44 LTE B26\_QPSK15M\_Rear Face\_1cm\_Ch26765\_1RB\_OS37

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	BACK, 10.00	Band 26	LTE-FDD, -	821.500, 26765	8.95	0.930	42.6

## Hardware Setup

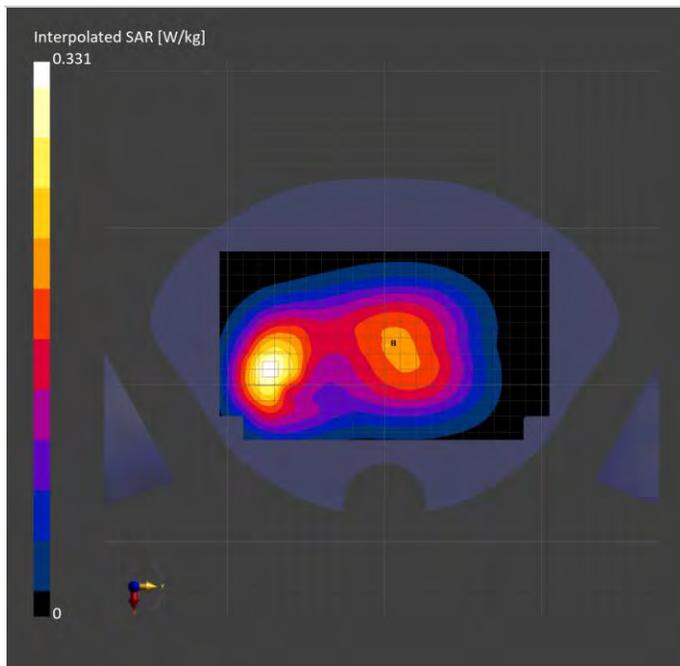
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL835-2025-08-24	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-24	2025-08-24
psSAR1g [W/kg]	0.282	0.294
psSAR10g [W/kg]	0.182	0.175
Power Drift [dB]	0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		14.0



# P45 LTE B41\_QPSK20M\_Bottom Side\_1cm\_Ch39750\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	Band 41	LTE-TDD,	2506.000, 39750	6.55	1.92	38.5

## Hardware Setup

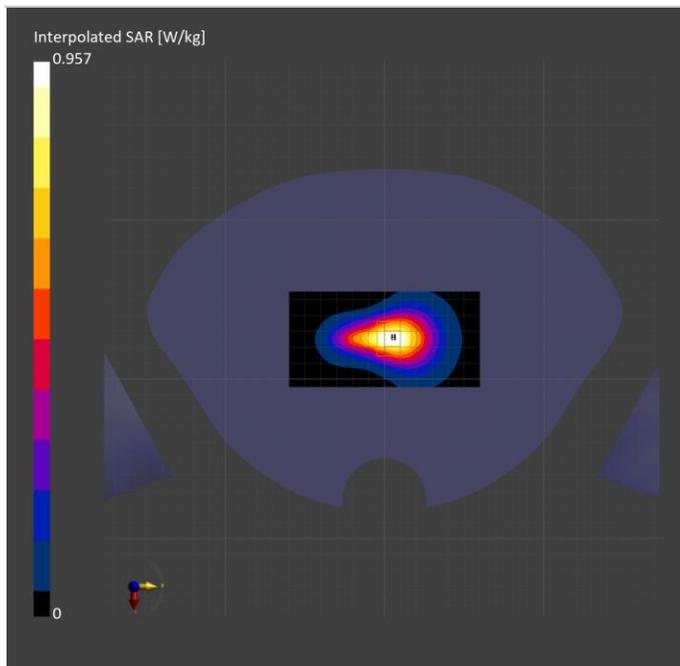
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2550-2025-09-04	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-04	2025-09-04
psSAR1g [W/kg]	0.755	0.782
psSAR10g [W/kg]	0.375	0.392
Power Drift [dB]	-0.01	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.8
Dist 3dB Peak [mm]		10.5



# P46 LTE B66\_QOSK20M\_Bottom Side\_1cm\_Ch132072\_50RB\_OS25

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	EDGE BOTTOM, 10.00	Band 66	LTE-FDD,	1720.000, 132072	7.45	1.30	38.3

## Hardware Setup

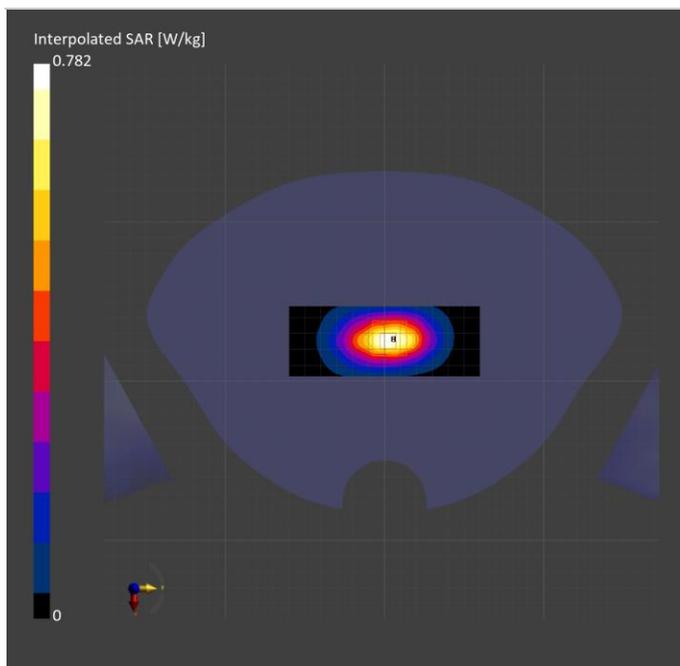
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL1750-2025-09-02	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	44.0 x 120.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	11.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-02	2025-09-02
psSAR1g [W/kg]	0.628	0.664
psSAR10g [W/kg]	0.336	0.364
Power Drift [dB]	-0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.5
Dist 3dB Peak [mm]		10.3



# P47 WLAN2.4G\_802.11b\_Right Side\_1cm\_Ch6

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	WLAN 2.4GHz	WLAN, -	2437.000, 6	6.67	1.82	38.4

## Hardware Setup

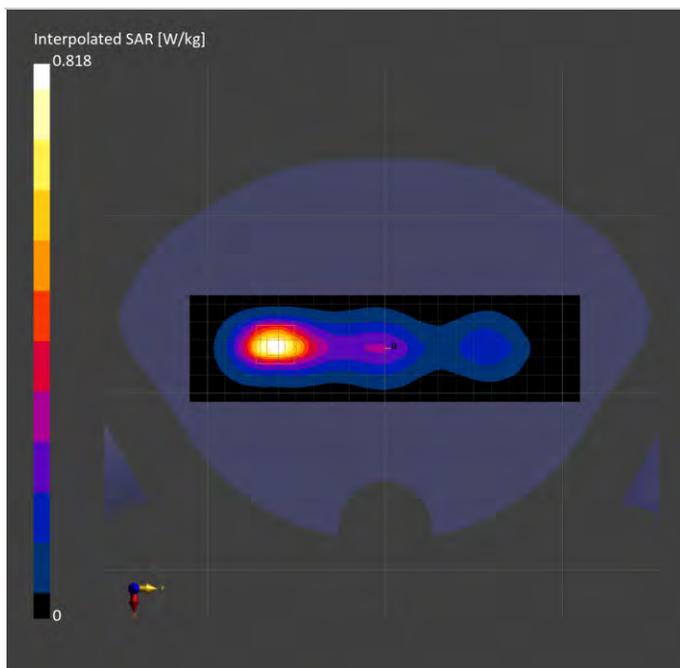
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	All points	All points
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.623	0.645
psSAR10g [W/kg]	0.291	0.298
Power Drift [dB]	-0.00	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.7
Dist 3dB Peak [mm]		8.1



# P48 WLAN5G\_802.11a\_Top Side\_1cm\_Ch48

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	WLAN 5GHz	WLAN, -	5240.000, 48	5.14	4.59	35.2

## Hardware Setup

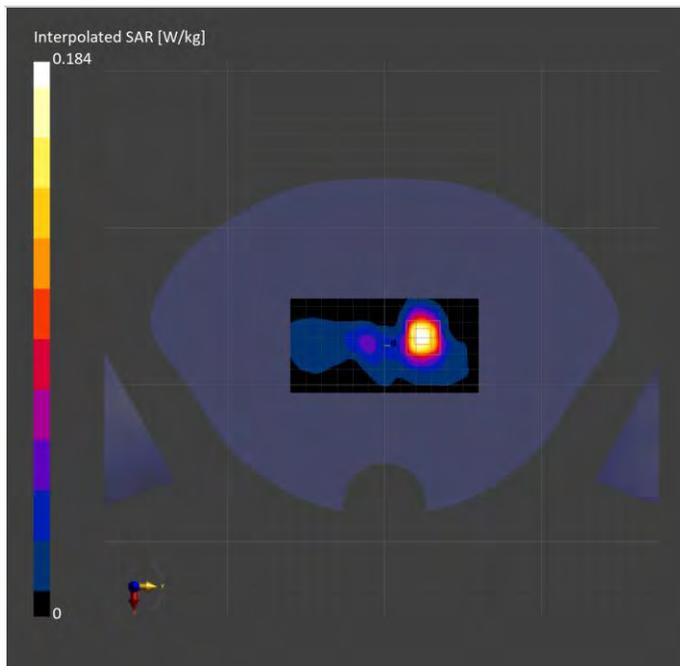
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-08-31	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-31	2025-08-31
psSAR1g [W/kg]	0.136	0.156
psSAR10g [W/kg]	0.049	0.049
Power Drift [dB]	0.06	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		57.9
Dist 3dB Peak [mm]		8.9



# P49 WLAN5G\_802.11a\_Top Side\_1cm\_Ch165

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE TOP, 10.00	WLAN 5GHz	WLAN, -	5240.000, 48	5.14	4.59	35.2

## Hardware Setup

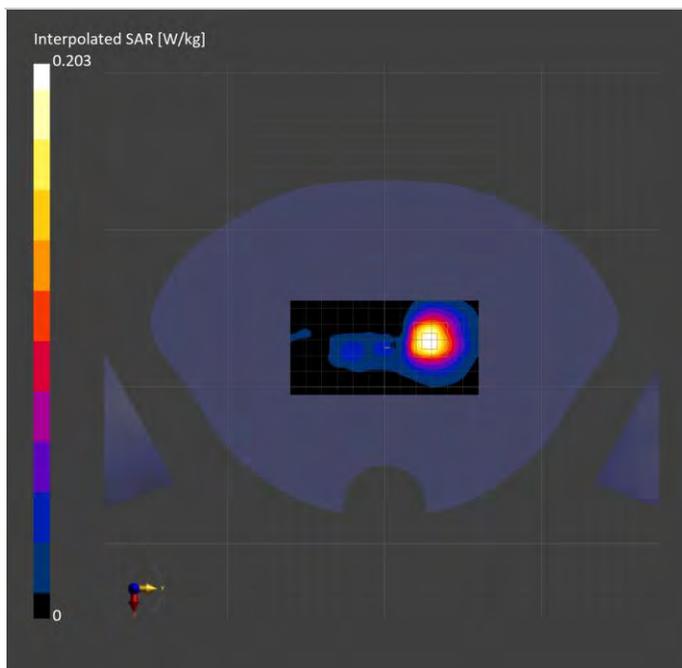
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL5G-2025-09-01	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 120.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-01	2025-09-01
psSAR1g [W/kg]	0.152	0.116
psSAR10g [W/kg]	0.058	0.056
Power Drift [dB]	0.03	-0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		54.0
Dist 3dB Peak [mm]		10.7



# P50 BT\_GFSK\_Right Side\_1cm\_Ch39

## Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	172.0 x 82.0 x 11.0		Phone

## Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, -	EDGE RIGHT, 10.00	ISM 2.4 GHz Band	Bluetooth, -	2441.000, 39	6.69	1.82	38.4

## Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V8.0 (30deg probe tilt) - 2135	HSL2450-2025-08-30	EX3DV4 - SN7801, 2025-07-22	DAE4 Sn1778, 2025-02-17

## Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	60.0 x 220.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Y	Y
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

## Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.086	0.084
psSAR10g [W/kg]	0.039	0.038
Power Drift [dB]	-0.05	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.6
Dist 3dB Peak [mm]		9.0

